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(12) United States Design Patent
Teranishi et al.

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(54) **PROBE PIN**

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(73) Assignee: **OMRON Corporation**, Kyoto (JP)

(**) Term: **15 Years**

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(30) **Foreign Application Priority Data**

Feb. 15, 2016 (JP) 2016-003163

(51) **LOC (10) Cl.** **10-04**
(52) **U.S. Cl.**
USPC **D10/80**
(58) **Field of Classification Search**
USPC D10/78, 80
CPC G01R 1/067; G01R 1/06705; G01R 1/06711; G01R 1/06716; G01R 1/06722; G01R 1/06727; G01R 1/06733; G01R 1/06738; G01R 1/06744; G01R 1/0675; G01R 1/06766; G01R 1/06772; G01R 1/06777; G01R 1/06783; G01R 1/0678
See application file for complete search history.

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(57) **CLAIM**

The ornamental design for a probe pin, as shown.

DESCRIPTION

FIG. **1** is a front, top, and right side perspective view of a probe pin showing our new design;
FIG. **2** is a front view thereof;
FIG. **3** is a rear view thereof;
FIG. **4** is a left side view thereof;
FIG. **5** is a right side view thereof;
FIG. **6** is a top view thereof; and,
FIG. **7** is a bottom view thereof.

1 Claim, 5 Drawing Sheets

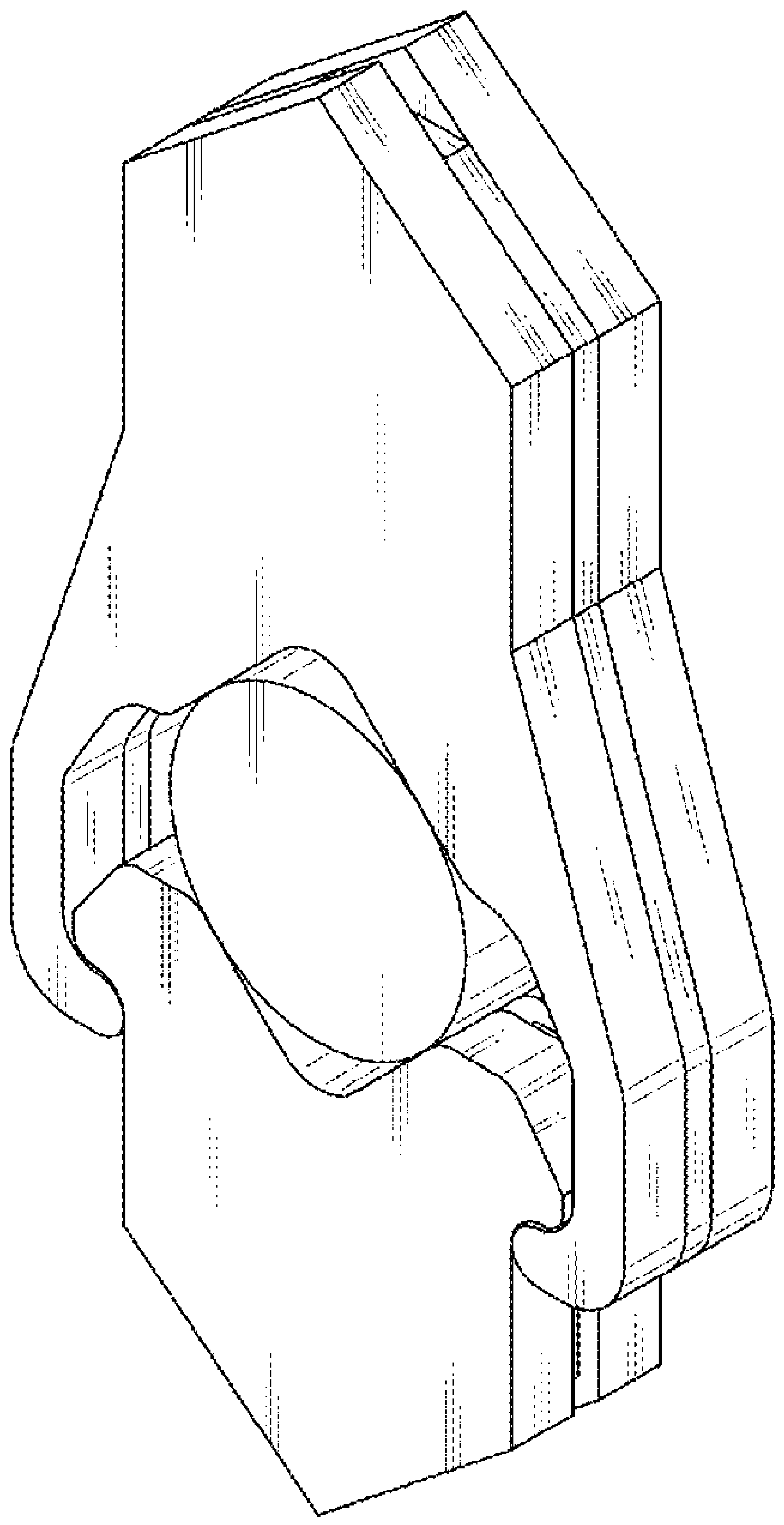

Fig. 1

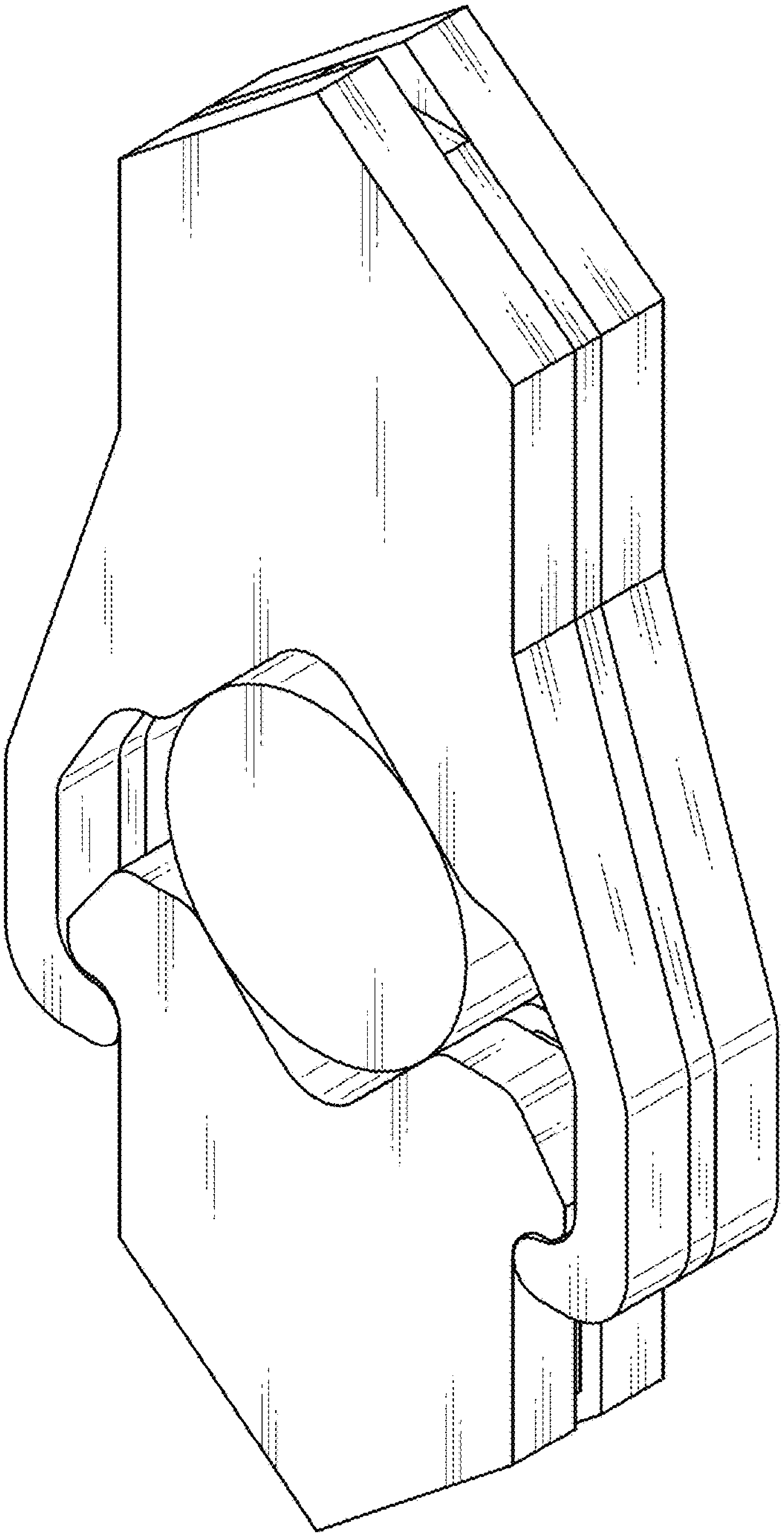

Fig. 2

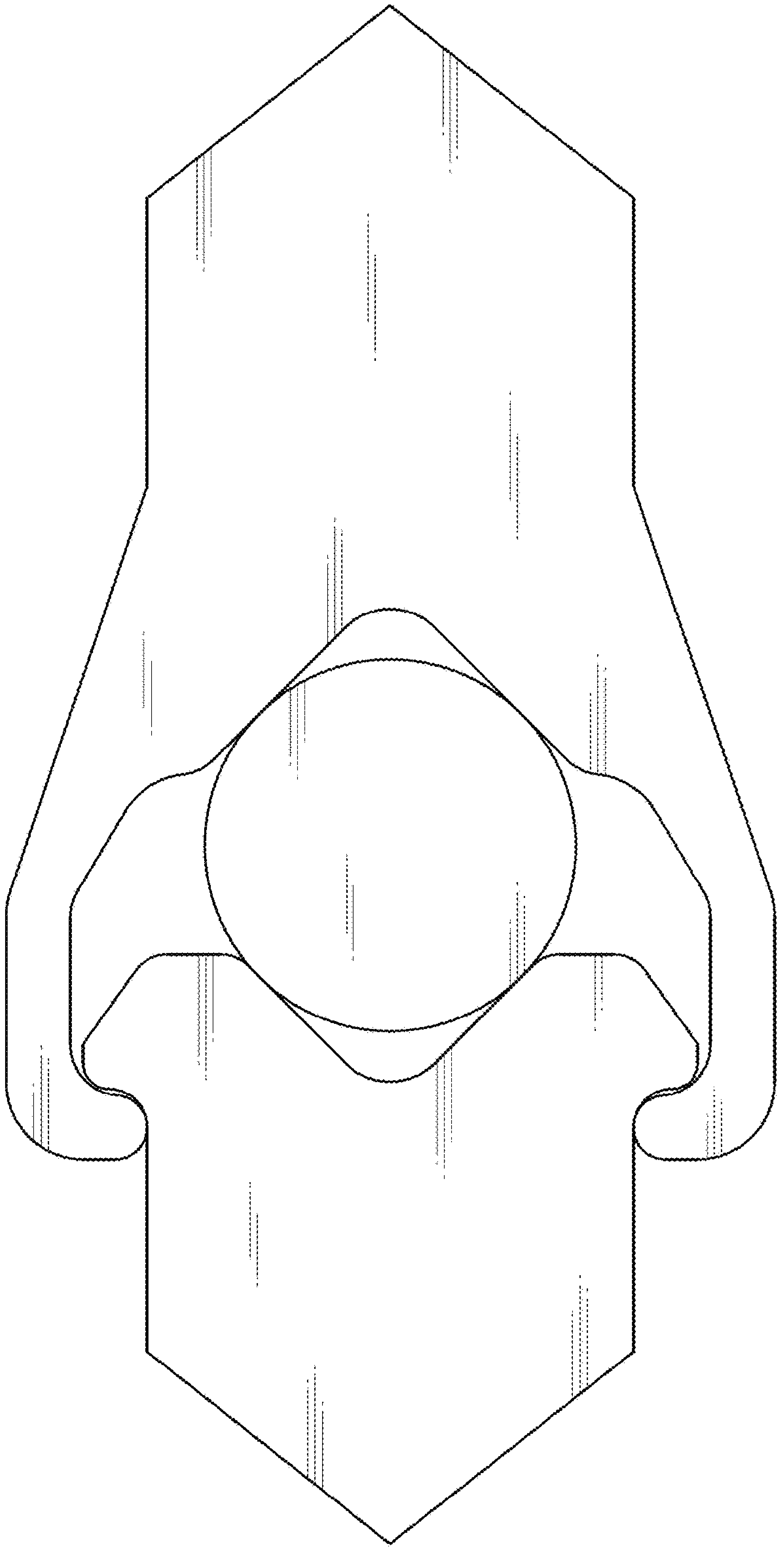

Fig. 3

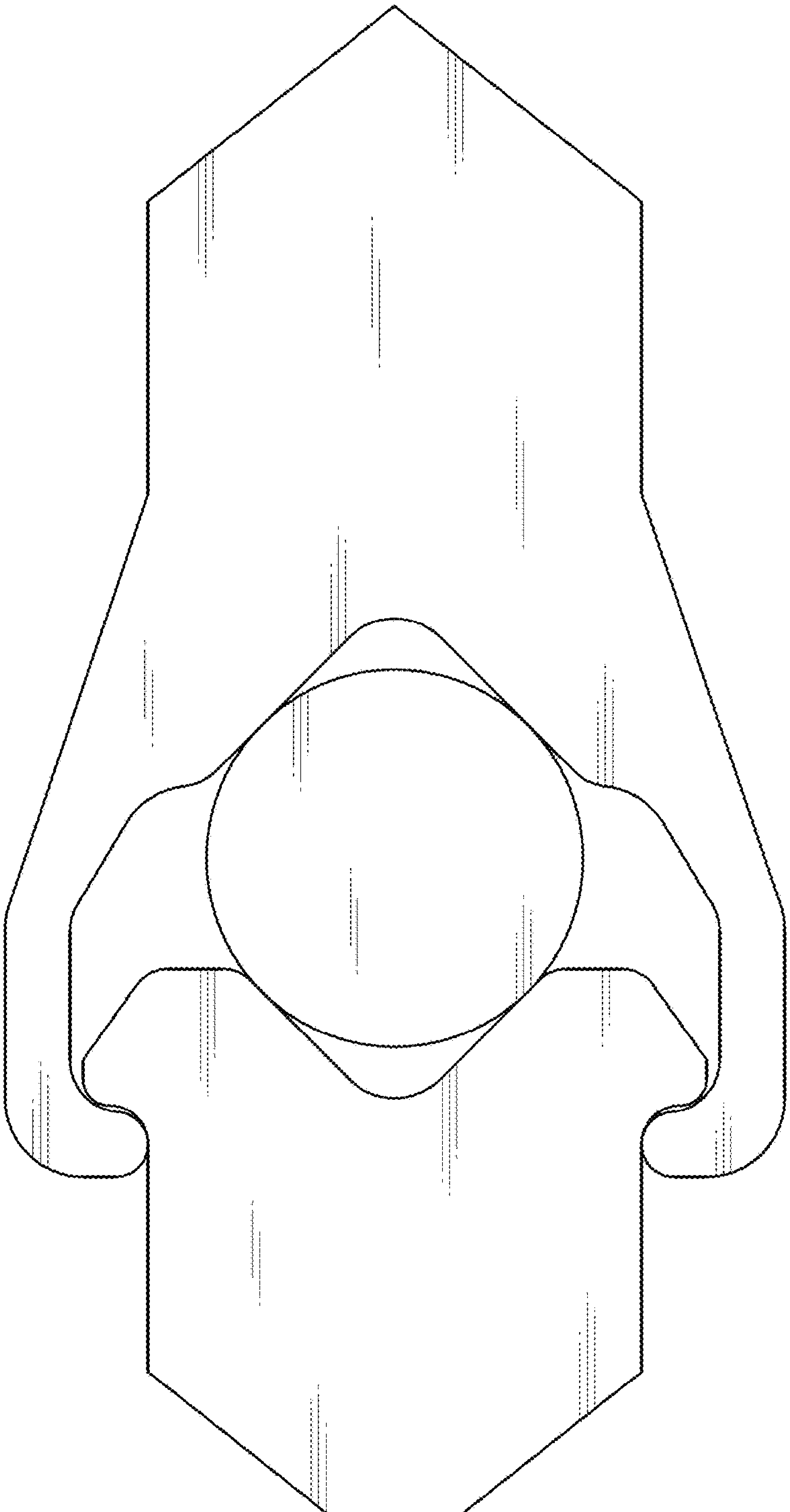

Fig. 4

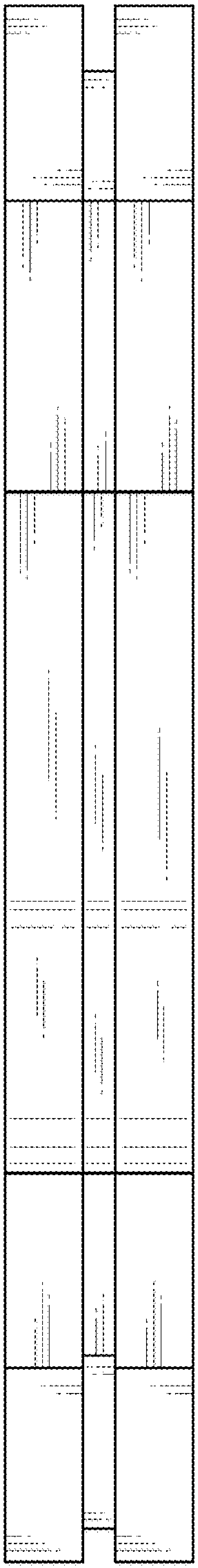

Fig. 5

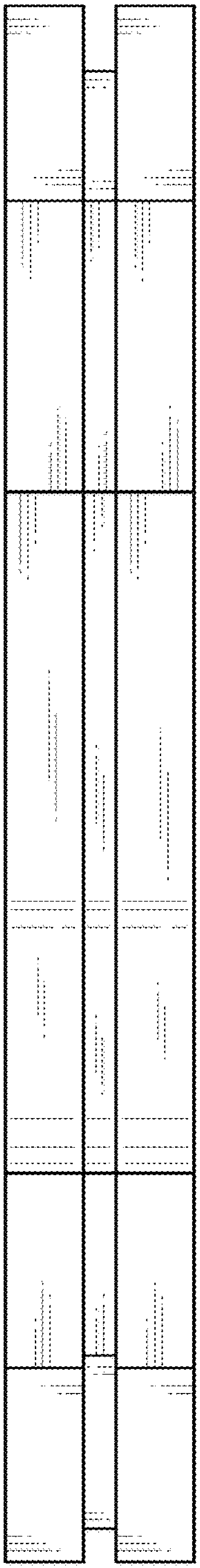

Fig. 6

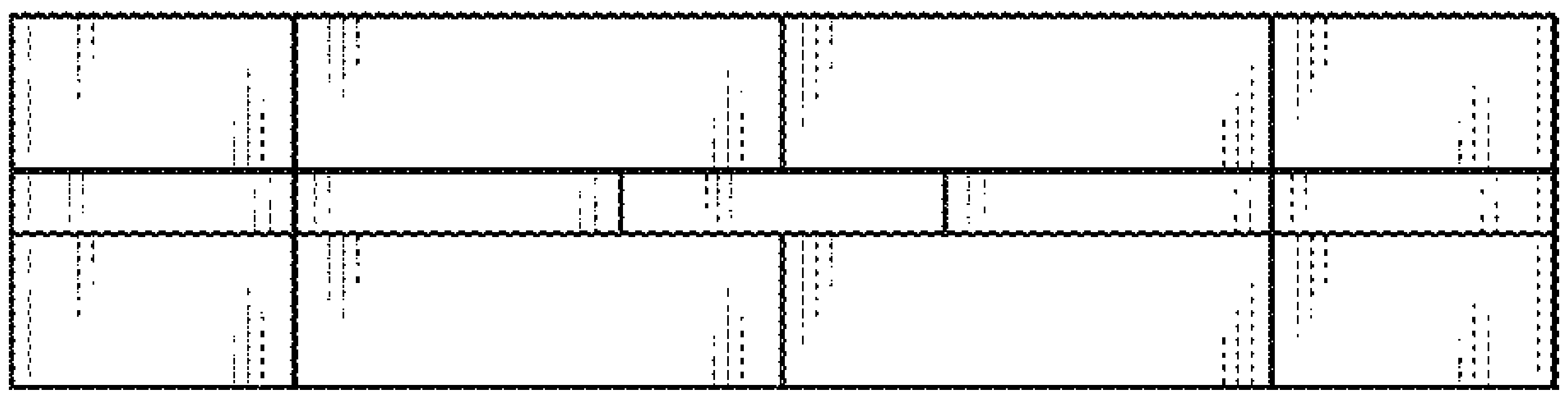

Fig. 7